捷多邦,**SMS4世VFT162244A**对**SM74**世VT162244A 3.3-V ABT 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

SN54LVT162244A . . . WD PACKAGE

SN74LVT162244A . . . DGG, DGV, OR DL PACKAGE

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- Members of the Texas Instruments
 Widebus™ Family
- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low Static-Power Dissipation
- Output Ports Have Equivalent 22-Ω Series Resistors, So No External Resistors Are Required
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V V_{CC})
- Support Unregulated Battery Operation Down to 2.7 V
- Typical V_{OLP} (Output Ground Bounce)
 <0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- I_{off} and Power-Up 3-State Support Hot Insertion
- Distributed V_{CC} and GND Pins Minimize High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

NOTE: For tape and reel order entry:

The DGGR package is abbreviated to GR, and the DGVR package is abbreviated to VR.

description

The 'LVT162244A devices are 16-bit buffers and line drivers designed for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment. These devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide true outputs and symmetrical active-low output-enable (\overline{OE}) inputs.

The outputs, which are designed to source or sink up to 12 mA, include equivalent $22-\Omega$ series resistors to reduce overshoot and undershoot.

TEXAS

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

((TOP VIEW)							
	U	h	-471					
1 <u>OE</u> L	1	- h	20E					
1Y1 L	2	47	1A1					
1Y2	3	46	1A2					
GND	4	45	GND					
1Y3 L	5	44	1A3					
1Y4 🛚	6	43	1A4					
v _{cc} [7	42	V_{CC}					
2Y1 🛚	8	41	2A1					
2Y2 🛚	9	40	2A2					
GND [10	39	GND					
2Y3 🛚	11	38	2A3					
2Y4 L	12		2A4					
3Y1 L	13		3A1					
3Y2	14	35	3A2					
GND [15	34	GND					
3Y3 L	16	33	3A3					
3Y4 L	17	32	3A4					
v _{cc} [18	31	V_{CC}					
4Y1 🛚	19	30	4A1					
4Y2 🛚	20	29	4A2					
GND [21	28	GND					
4Y3 🛚	22	27	4A3					

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description (continued)

When V_{CC} is between 0 and 1.5 V, the devices are in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

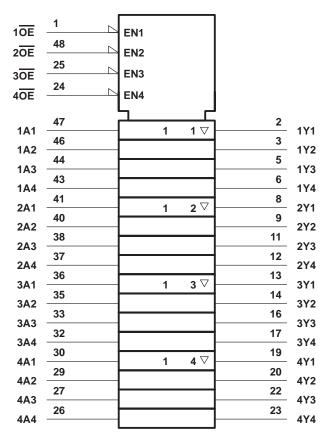
These devices are fully specified for hot-insertion applications using I_{off} and power-up 3-state. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict.

The SN54LVT162244A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LVT162244A is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each 4-bit buffer/driver)

INP	JTS	OUTPUT
OE	Α	Y
L	Н	Н
L	L	L
Н	Χ	Z

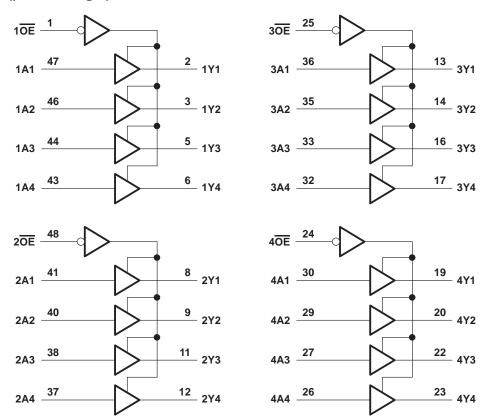
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	
Input voltage range, V _I (see Note 1)	0.5 V to 7 V
Voltage range applied to any output in the high-impedance	
or power-off state, V _O (see Note 1)	
Voltage range applied to any output in the high state, V _O (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Current into any output in the low state, I _O	30 mA
Current into any output in the high state, I _O (see Note 2)	30 mA
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	70°C/W
DGV package	58°C/W
DL package	63°C/W
Storage temperature range, T _{stg}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

- 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
- 3. The package thermal impedance is calculated in accordance with JESD 51.



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recommended operating conditions (see Note 4)

			SN54LVT1	62244A	SN74LVT1	UNIT	
			MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage		2.7	3.6	2.7	3.6	V
V _{IH}	High-level input voltage		2	, S	2		V
V _{IL}	Low-level input voltage		0.8		0.8	V	
VI	Input voltage			5.5		5.5	V
IOH	High-level output current		6	– 12		-12	mA
loL	Low-level output current		720	12		12	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled	60%	10		10	ns/V
Δt/ΔV _{CC}	Power-up ramp rate		200		200		μs/V
T _A	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54	SN54LVT162244A			SN74LVT162244A			
		lesi Co	TEST CONDITIONS			MAX	MIN	TYP [†]	MAX	UNIT	
V_{IK} $V_{CC} = 2.7 \text{ V}, I_{I} = -18 \text{ mA}$		I _I = -18 mA			-1.2			-1.2	V		
Vон		$V_{CC} = 3 \text{ V}, \qquad I_{OH} = -12 \text{ mA} \qquad 2 \qquad 2$		V							
VOL		V _{CC} = 3 V,	I _{OL} = 12 mA			0.8			0.8	V	
		$V_{CC} = 0 \text{ or } 3.6 \text{ V},$	V _I = 5.5 V			10			10		
١.	Control inputs	V _{CC} = 3.6 V,	$V_I = V_{CC}$ or GND		±1			±1			
1	Bata innuts	Vac = 3.6.V	VI = VCC			1	1			μΑ	
Data inputs		V _{CC} = 3.6 V	V _I = 0		-5			- 5			
l _{off}		$V_{CC} = 0$, $V_I \text{ or } V_O = 0 \text{ to } 4.5 \text{ V}$			2			±100			
lozh		V _{CC} = 3.6 V,	V _O = 3 V		Ź	5			5	μΑ	
lozL		$V_{CC} = 3.6 \text{ V}, \qquad V_{O} = 0.5 \text{ V}$		-5			- 5			μΑ	
lozpu		$\frac{\text{V}_{\text{CC}}}{\text{OE}} = 0 \text{ to } 1.5 \text{ V}, \text{ V}_{\text{O}} = 0.5 \text{ V to } 3 \text{ V},$ $\frac{\text{OE}}{\text{OE}} = \text{don't care}$		±100*		±100*	±100		μΑ		
IOZPD		$\frac{V_{CC}}{OE}$ = 1.5 V to 0, V_{O} = $\frac{V_{CC}}{OE}$ = don't care	$\frac{V_{CC}}{OE}$ = 1.5 V to 0, V_{O} = 0.5 V to 3 V, OE = don't care		±100*			±100			
		V _{CC} = 3.6 V,	Outputs high	4		0.19			0.19		
Icc		$I_O = 0$,	Outputs low		Ę			5			
		$V_I = V_{CC}$ or GND	Outputs disabled			0.19	0.19				
ΔI _{CC} ‡		$V_{CC} = 3 \text{ V to } 3.6 \text{ V, One input at } V_{CC} - 0.6 \text{ V,}$ Other inputs at V_{CC} or GND				0.2			0.2	mA	
Ci	C _i V _I = 3 V or 0			4			4				
C_0 $V_0 = 3 \text{ V or } 0$			9			9		pF			

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.



[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$. ‡ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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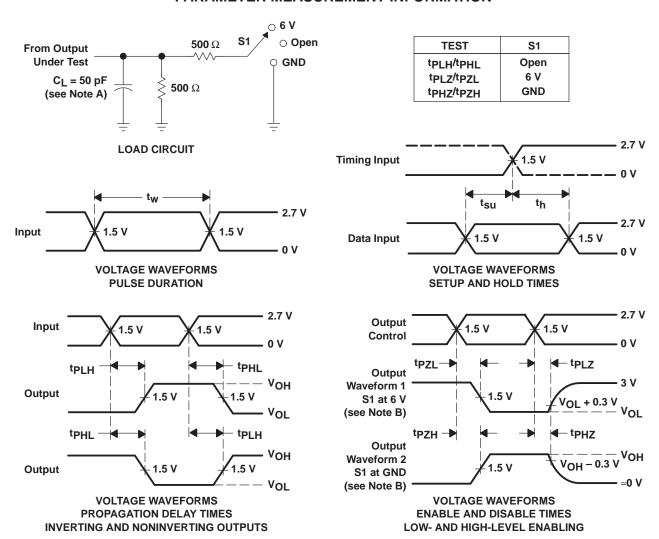
switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

				SN54LVT162244A								
PARAMETER FROM TO (OUTPUT)		V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V			V _{CC} = 2.7 V		UNIT	
			MIN	MAX	MIN	MAX	MIN	TYP†	MAX	MIN	MAX	
tPLH	А	~	1.1	4.6	2	5.1	1.4	3.4	4		4.8	ns
^t PHL		'	1.1	3.9	4	4.5	1.2	2.9	3.6		4.1	115
^t PZH	ŌĒ	Y	1.1	5.4	48	6.7	1.2	3.9	5.1		6.5	ns
tPZL		'	1.3	4.9	V ,	6.1	1.4	3.8	4.5		5.8	115
^t PHZ	ŌĒ	~	1.6	5.9		6.5	2.2	4.4	5		5.4	ns
t _{PLZ}		1	1	5.9		5.8	2	4.2	5		5.4	115
tsk(o)				0		·			0.5			ns

 $[\]uparrow$ All typical values are at V_{CC} = 3.3 V, T_A = 25°C.

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 2.5 ns. $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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